



US00D332574S

United States Patent [19] Chang

[11] Patent Number: Des. 332,574
[45] Date of Patent: ** Jan. 19, 1993

[54] CLAMP MULTIMETER

[75] Inventor: Shang-Wen Chang, Taipei Hsien, Taiwan

[73] Assignee: APPA Technology Corporation, Taiwan

[**] Term: 14 Years

[21] Appl. No.: 655,979

[22] Filed: Feb. 15, 1991

[52] U.S. Cl. D10/78; D10/79

[58] Field of Search D10/46, 78, 79, 80;
324/126, 127, 128, 129, 130, 117 H, 72.5, 73 R,
133, 149, 156, 158 P, 158 F

[56] References Cited

U.S. PATENT DOCUMENTS

D. 213,878 4/1969 Shimasaki D10/79
D. 219,217 11/1970 Sakow D10/79

D. 264,448 5/1982 Kuramoto D10/79
D. 312,420 11/1990 Kuramoto D10/79
4,071,824 1/1978 Kernander et al. D10/79 X
4,283,677 8/1981 Niwa D10/79 X

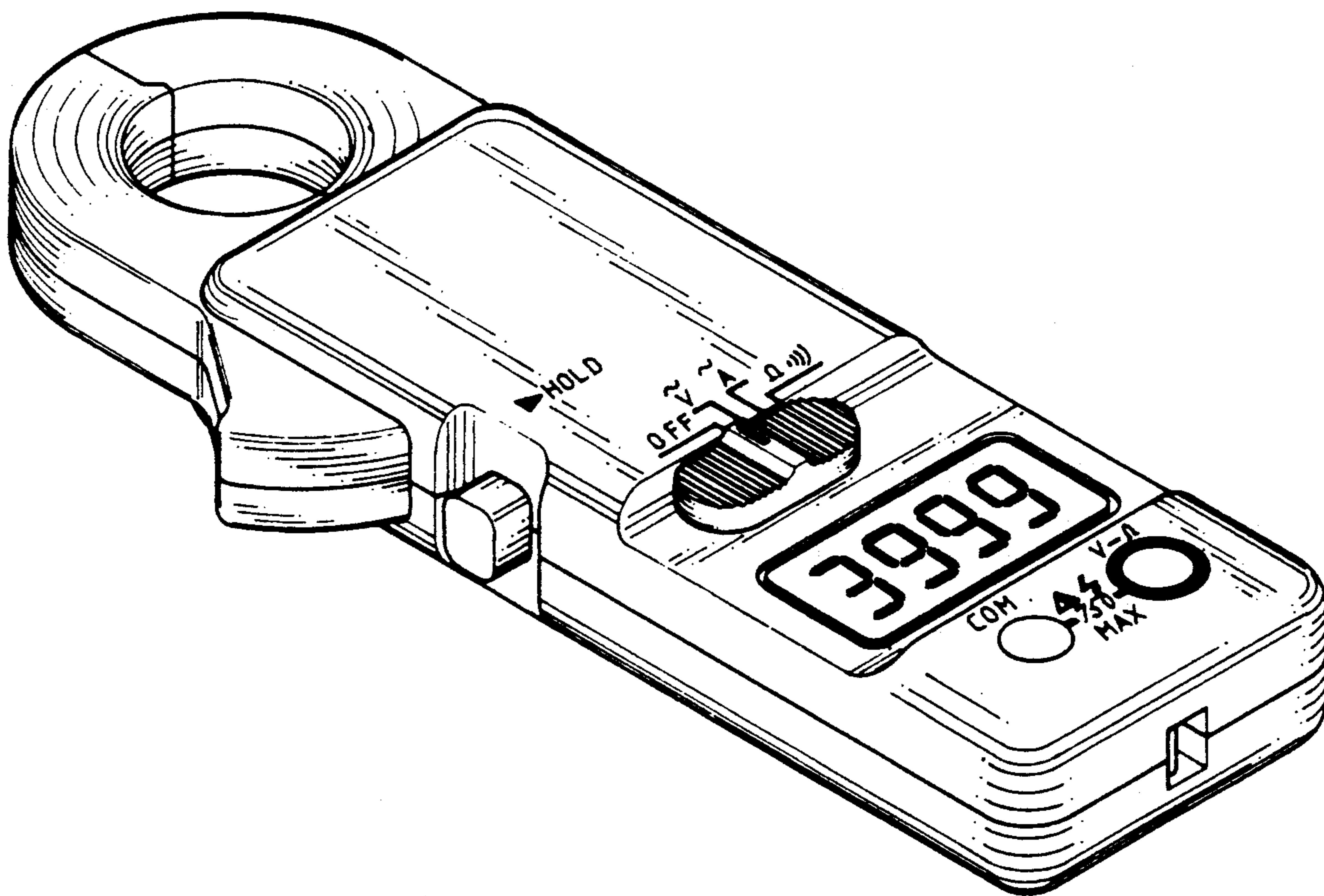
Primary Examiner—Alan P. Douglas
Assistant Examiner—Antoine D. Davis
Attorney, Agent, or Firm—Clifford A. Poff

[57] CLAIM

The ornamental design for the clamp multimeter, as shown and described.

DESCRIPTION

FIG. 1 is a top, front left side perspective view of a clamp multimeter showing my new design; FIG. 2 is a front elevational view; FIG. 3 is a rear elevational view; FIG. 4 is a right side elevational view; FIG. 5 is a left side elevational view; FIG. 6 is a top plan view; and, FIG. 7 is a bottom plan view thereof.



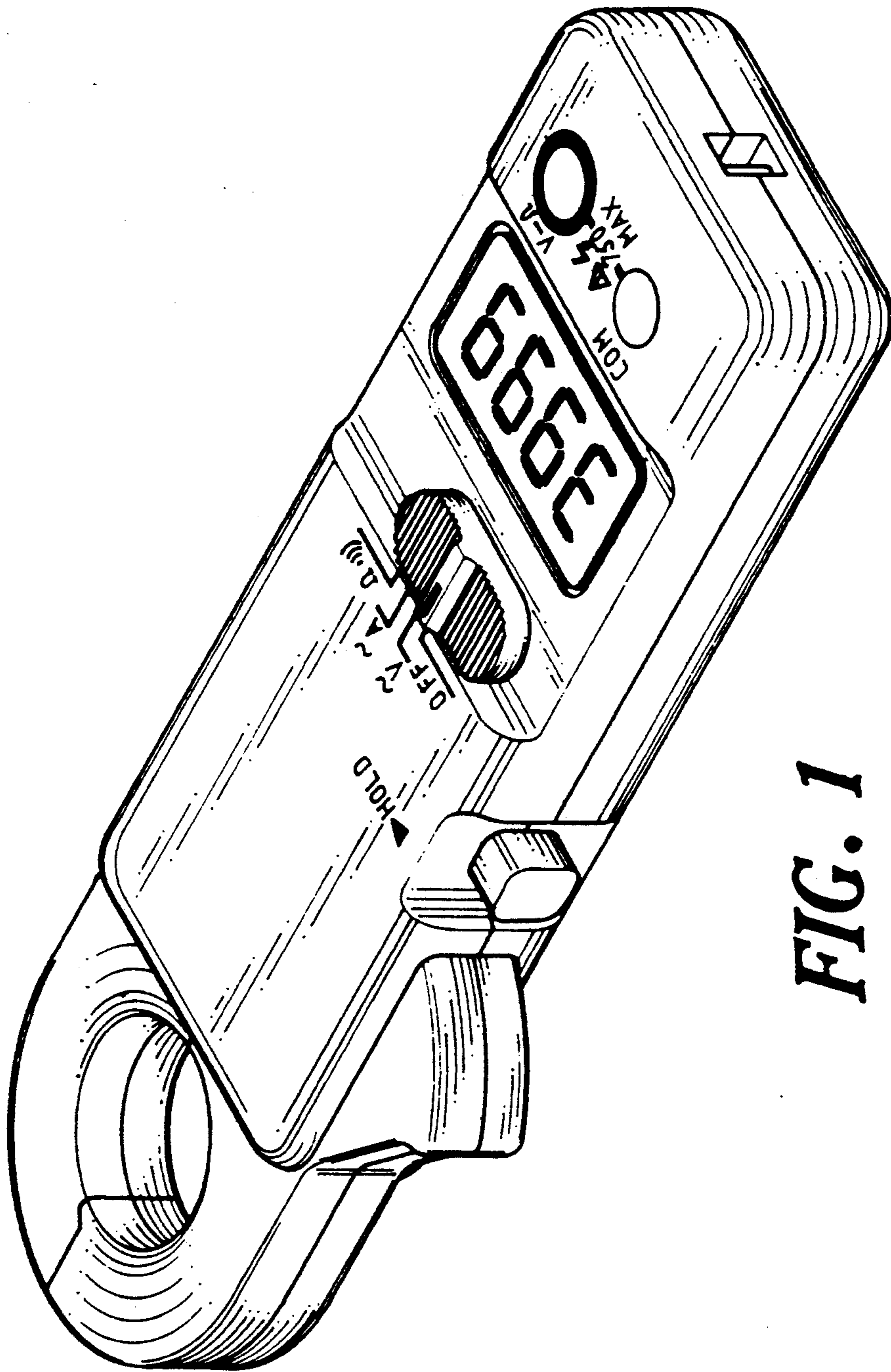


FIG. 1

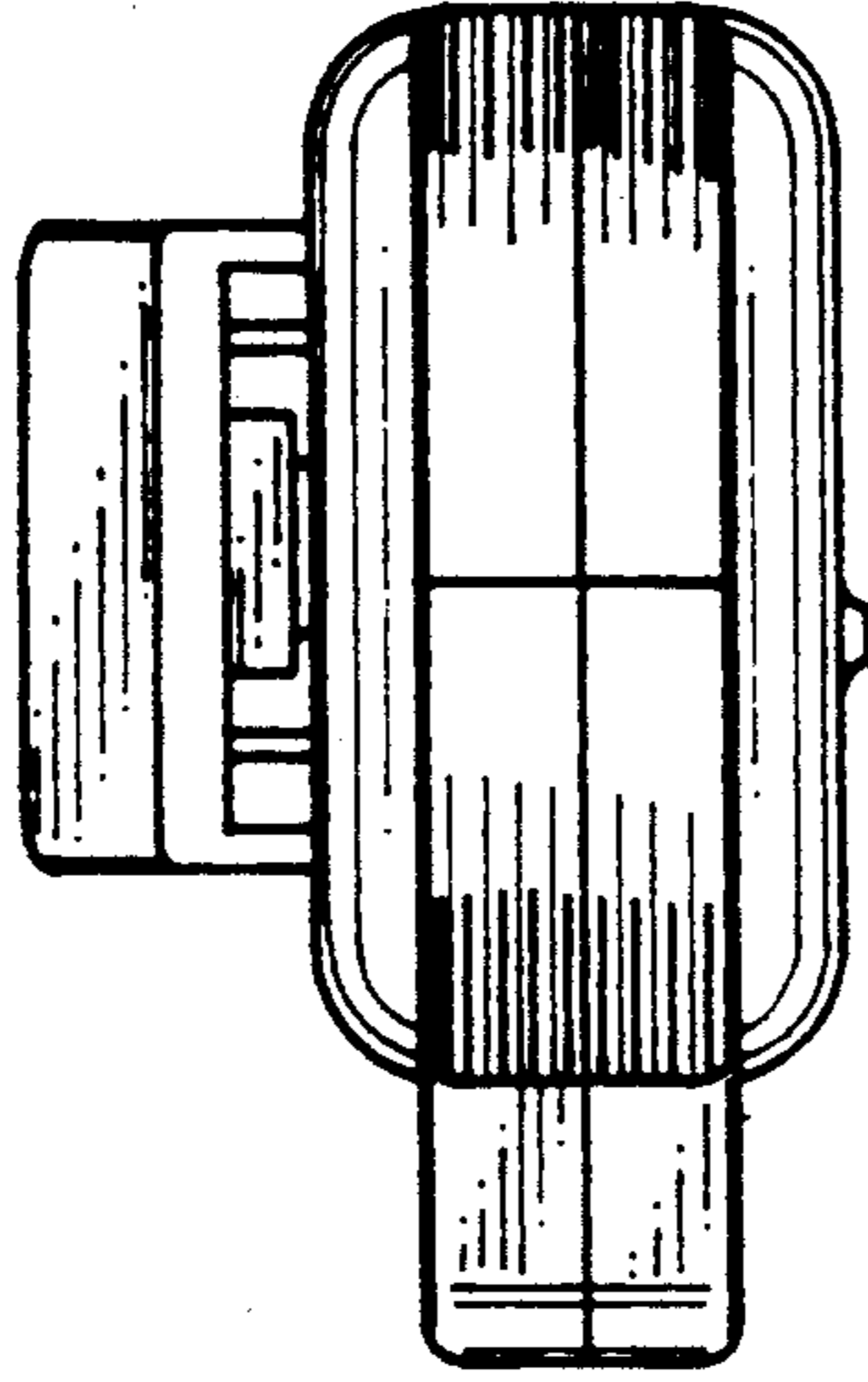


FIG. 3

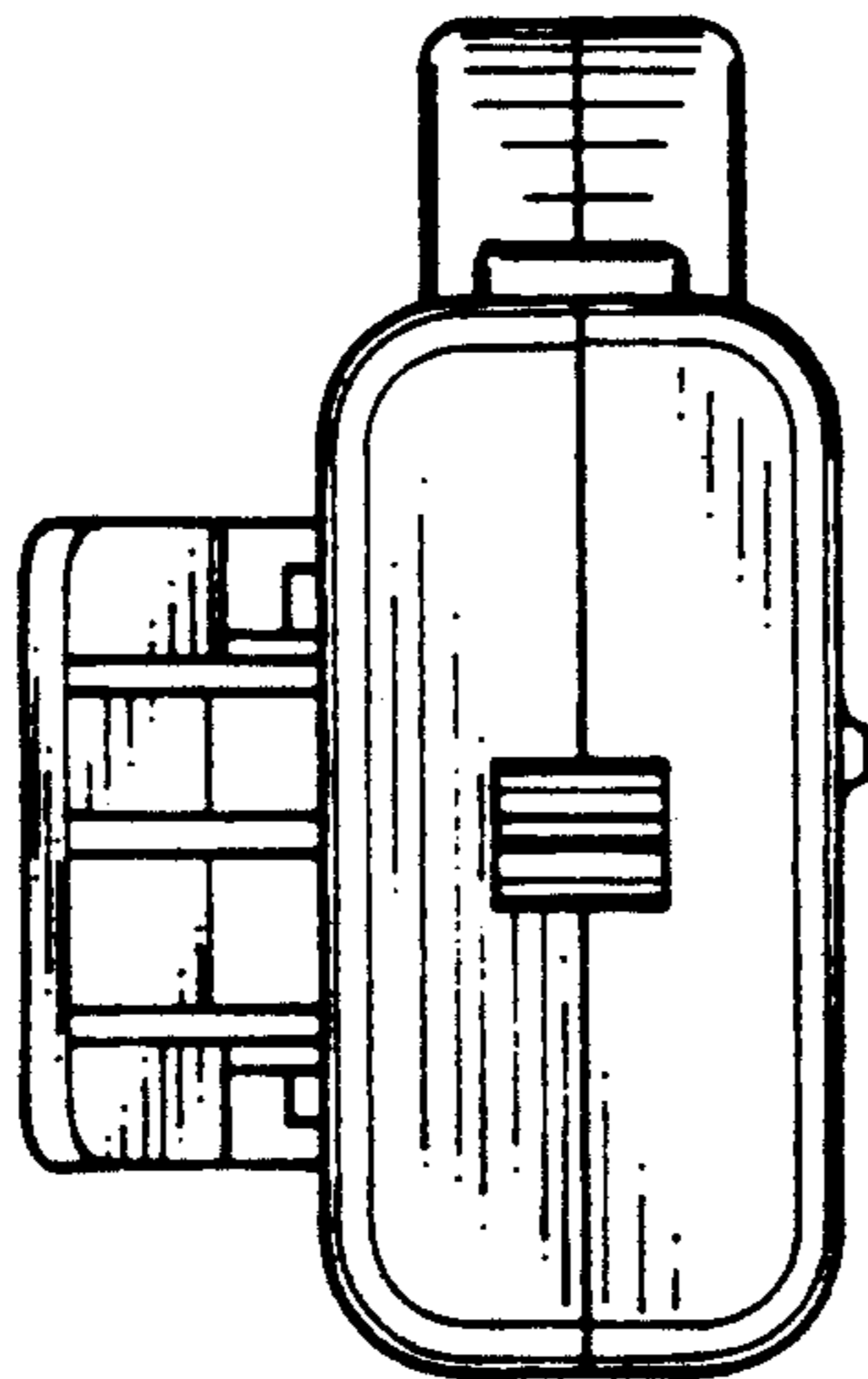


FIG. 2

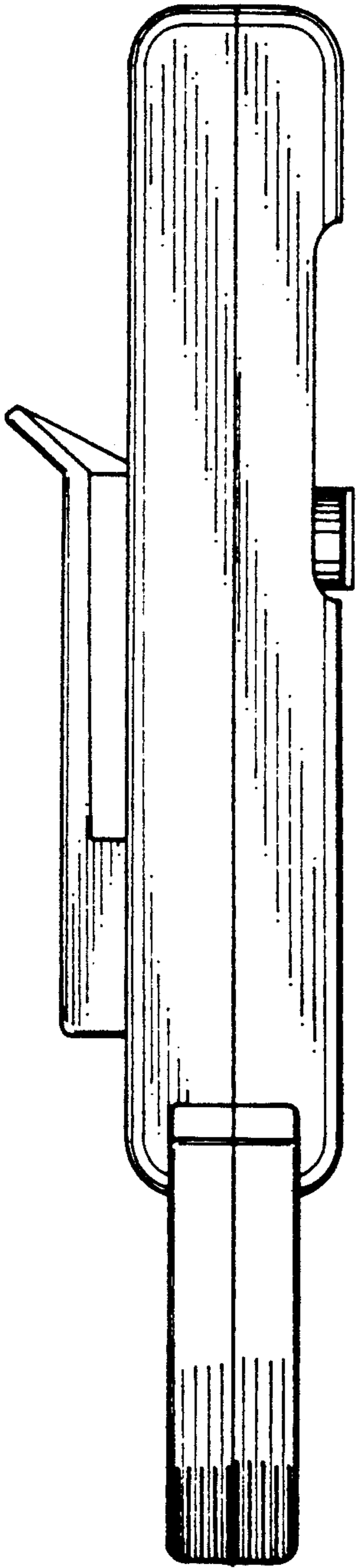


FIG. 4

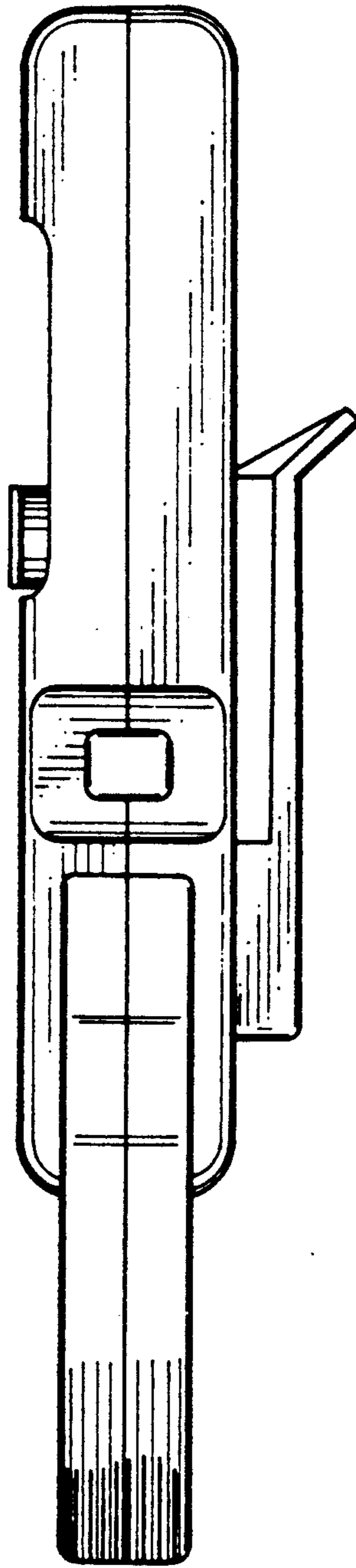


FIG. 5

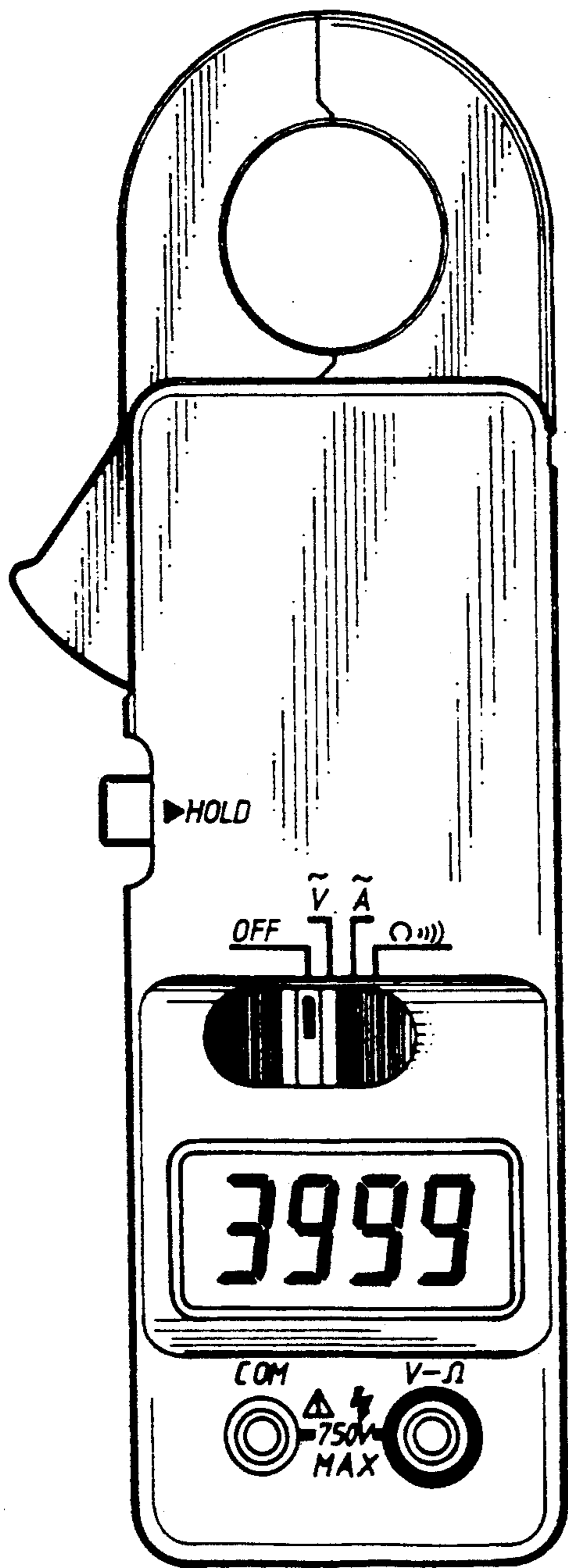


FIG. 6

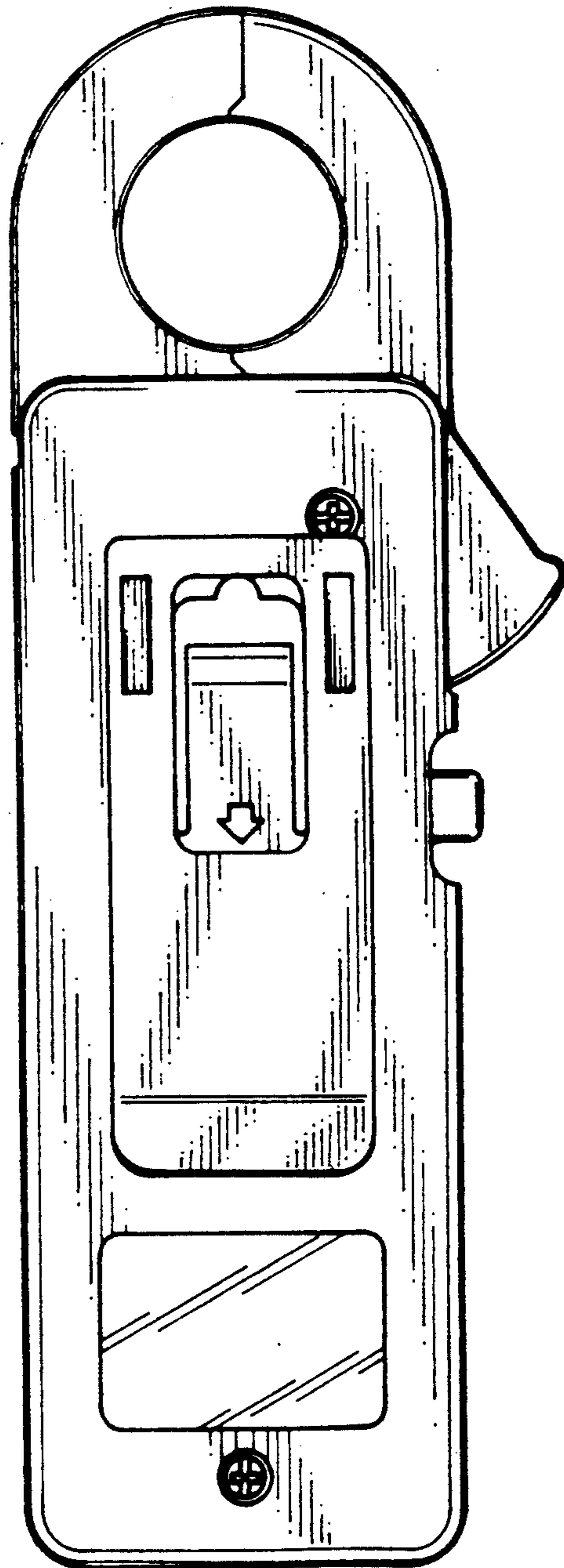


FIG. 7